

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/764,302	TSUCHIMURA ET AL.
	Examiner Le Nguyen	Art Unit 2174

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
US-PPGPUB; USPAT: 715/788,792		6/23/2006	LVN